



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Robert P. Meagley Et Al.  
Serial No.: 10/688,521  
Filed: October 17, 2003  
For: Reducing Photoresist Line  
Edge Roughness Using  
Chemically-Assisted Reflow

§ Group Art Unit:  
§  
§  
§ Examiner:  
§  
§  
§ Atty. Dkt. No.: ITL.1026US  
§ (P16713)  
§

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

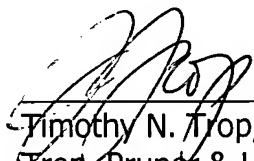
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Dear Sir:

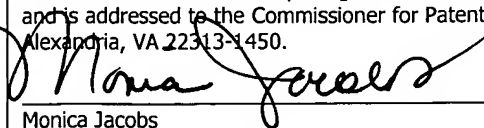
Applicant submits the references listed on the attached form PTO 1449, copies of which are enclosed. A copy of a communication dated March 18, 2005 from a foreign patent office in a counterpart application is also enclosed. I, the undersigned, hereby certify that each item of information contained in the Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement. Please apply any charges or credits to Deposit Account No. 20-1504 (ITL.1026US).

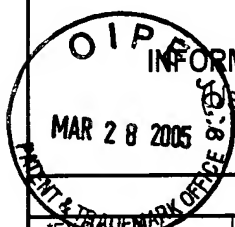
Respectfully submitted,

March 24, 2005  
Date

  
Timothy N. Trop, Reg. No. 28,994  
Trop, Pruner & Hu, P.C.  
8554 Katy Freeway, Ste. 100  
Houston, TX 77024  
713/468-8880  
713/468-8883 [fax]

Customer No.  
**21906**

Date of Deposit: March 24, 2005  
I hereby certify under 37 CFR 1.8(a) that this correspondence is being deposited with the United States Postal Service as **first class mail** with sufficient postage on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.  
  
Monica Jacobs

**INFORMATION DISCLOSURE CITATION**

(Use several sheets if necessary)

ATTY DOCKET NO.

ITL.1026US (P16713)

SERIAL NO.

10/688,521

APPLICANT(S):

Robert P. Meagley et al.

FILING DATE:

October 17, 2005

GROUP ART UNIT:

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A.	6,582,891	06/24/03	Hallock et al.			
	B.						
	C.						
	D.						
	E.						

**U.S. PATENT APPLICATION PUBLICATIONS**

	F.	2002/0184788	12/12/2002	Kawakami et al.			
	G.	2003/0027080	02/06/03	Lu			
	H.						
	I.						
	J.						

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	K.							
	L.							
	M.							
	N.							
	O.							

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

	P.	
	Q.	
	R.	
	S.	
	T.	
	U.	
	V.	

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.